

“Atomic-scale identification of novel planar defect phases in heteroepitaxial $\text{YBa}_2\text{Cu}_3\text{O}_{7-\delta}$ thin films”. Gauquelin N, Zhang H, Zhu G, Wei JYT, Botton GA, AIP advances **8**, 055022 (2018). <http://doi.org/10.1063/1.5011761>